

Ultrafast 3.3 V/5 V Single-Supply SiGe Comparators

ADCMP572/ADCMP573

FEATURES

3.3 V/5.2 V single-supply operation 150 ps propagation delay 15 ps overdrive and slew rate dispersion 8 GHz equivalent input rise time bandwidth 80 ps minimum pulse width 35 ps typical output rise/fall 10 ps deterministic jitter (DJ) 200 fs random jitter (RJ) On-chip terminations at both input pins Robust inputs with no output phase reversal Resistor-programmable hysteresis Differential latch control Extended industrial −40°C to +125°C temperature range

APPLICATIONS

Clock and data signal restoration and level shifting Automatic test equipment (ATE) High speed instrumentation Pulse spectroscopy Medical imaging and diagnostics High speed line receivers Threshold detection Peak and zero-crossing detectors High speed trigger circuitry

GENERAL DESCRIPTION

The ADCMP572 and ADCMP573 are ultrafast comparators fabricated on Analog Devices' proprietary XFCB3 Silicon Germanium (SiGe) bipolar process. The ADCMP572 features CML output drivers and latch inputs, and the ADCMP573 features reduced swing PECL (RSPECL) output drivers and latch inputs.

Both devices offer 150 ps propagation delay and 80 ps minimum pulse width for 10 Gbps operation with 200 fs rms random jitter (RJ). Overdrive and slew rate dispersion are typically less than 15 ps.

A flexible power supply scheme allows both devices to operate with a single 3.3 V positive supply and a −0.2 V to +1.2 V input signal range or with split input/output supplies to support a wider −0.2 V to +3.2 V input signal range and an independent range of output levels. 50 Ω on-chip termination resistors are

Rev. A

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FUNCTIONAL BLOCK DIAGRAM

Figure 1.

provided at both inputs with the optional capability to be left open (on an individual pin basis) for applications requiring high impedance inputs.

The CML output stage is designed to directly drive 400 mV into 50 Ω transmission lines terminated to between 3.3 V to 5.2 V. The RSPECL output stage is designed to drive 400 mV into 50 Ω terminated to V_{CCO} – 2 V and is compatible with several commonly used PECL logic families. The comparator input stage offers robust protection against large input overdrive, and the outputs do not phase reverse when the valid input signal range is exceeded. High speed latch and programmable hysteresis features are also provided.

The ADCMP572 and ADCMP573 are available in a 16-lead LFCSP package and have been characterized over an extended industrial temperature range of −40°C to +125°C.

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REVISION HISTORY

4/09—Rev. 0 to Rev. A

4/05—Revision 0: Initial Version

ELECTRICAL CHARACTERISTICS

 $V_{\text{CCI}} = V_{\text{CCO}} = 3.3 \text{ V}$, $T_A = -40^{\circ}\text{C}$ to +125°C, typical at $T_A = +25^{\circ}\text{C}$, unless otherwise noted.

Table 1.

¹ Equivalent input bandwidth assumes a simple first-order response and is calculated with the following formula: BW_{EQ} = 0.22/√(tr_{COMP}2–tr_{IN}?), where tr_{IN} is the 20/80 transition time of a quasi-Gaussian signal applied to the comparator input, and tr_{COMP} is the effective transition time digitized by the comparator.

ABSOLUTE MAXIMUM RATINGS

Table 2.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

THERMAL CONSIDERATIONS

The ADCMP572/ADCMP573 LFCSP 16-lead package has a θ _{JA} (junction-to-ambient thermal resistance) of 70°C/W in still air.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

Figure 2. ADCMP572/ADCMP573 Pin Configuration

Table 3. Pin Function Descriptions

TYPICAL PERFORMANCE CHARACTERISTICS

 $V_{\text{CCI}} = V_{\text{CCO}} = 3.3 \text{ V}$, $T_A = 25^{\circ} \text{C}$, unless otherwise noted.

Figure 4. Propagation Delay vs. Input Common-Mode

Figure 5. Propagation Delay vs. Temperature

Figure 6. Rise/Fall Time vs. Temperature

04409-042

1409-042

04409-043

04409-043

Figure 7. Hysteresis vs. R_{HYS} Control Resistor

Figure 8. Hysteresis vs. R_{HYS} Sink Current

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04409-039

04409-040

Figure 9. Input Bias Current vs. Input Differential

Figure 10. Input Bias Current vs. Temperature

Figure 11. Input Offset Voltage vs. Temperature

Figure 12. Output Levels vs. Temperature

04409-046

Figure 13. ADCMP572 Eye Diagram at 2.5 Gbps

Figure 14. ADCMP572 Eye Diagram at 6.5 Gbps

APPLICATION INFORMATION **POWER/GROUND LAYOUT AND BYPASSING**

The ADCMP572/ADCMP573 comparators are very high speed SiGe devices. Consequently, it is essential to use proper high speed design techniques to achieve the specified performance. Of critical importance is the use of low impedance supply planes, particularly the output supply plane (V_{CCO}) and the ground plane (GND). Individual supply planes are recommended as part of a multilayer board. Providing the lowest inductance return path for switching currents ensures the best possible performance in the target application.

It is important to adequately bypass the input and output supplies. A 1 μF electrolytic bypass capacitor should be placed within several inches of each power supply pin to ground. In addition, multiple high quality 0.01 μF bypass capacitors should be placed as close as possible to each of the V_{CCI} and V_{CCO} supply pins and should be connected to the GND plane with redundant vias. High frequency bypass capacitors should be carefully selected for minimum inductance and ESR. Parasitic layout inductance should be avoided to maximize the effectiveness of the bypass at high frequencies.

If the input and output supplies are connected separately such that $V_{\text{CCI}} \neq V_{\text{CCO}}$, care should be taken to bypass each of these supplies separately to the GND plane. A bypass capacitor should not be connected between them. It is recommended that the GND plane separate the V_{CCI} and V_{CCO} planes when the circuit board layout is designed to minimize coupling between the two supplies and to take advantage of the additional bypass capacitance from each respective supply to the ground plane. This enhances the performance when split input/output supplies are used. If the input and output supplies are connected together for single-supply operation such that $V_{\text{CCI}} = V_{\text{CCO}}$, coupling between the two supplies is unavoidable; however, every effort should be made to keep the supply plane adjacent to the GND plane to maximize the additional bypass capacitance this arrangement provides.

CML/RSPECL OUTPUT STAGE

Specified propagation delay dispersion performance can be achieved only by using proper transmission line terminations. The outputs of the ADCMP572 are designed to directly drive 400 mV into 50 Ω cable, microstrip, or strip line transmission lines properly terminated to the V_{CCO} supply plane. The CML output stage is shown in the simplified schematic diagram of Figure 15. The outputs are each back terminated with 50 Ω for best transmission line matching. The RSPECL outputs of the ADCMP573 are illustrated in Figure 16 and should be terminated to $V_{\text{CCO}} - 2$ V. As an alternative, Thevenin equivalent termination networks can be used in either case if the direct termination voltage is not readily available. If high speed output signals must be routed more than a centimeter,

microstrip or strip line techniques are essential to ensure proper transition times and to prevent output ringing and pulse width dependent propagation delay dispersion. For the most timing critical applications where transmission line reflections pose the greatest risk to performance, the ADCMP572 provides the best match to 50 Ω output transmission paths.

Figure 15. Simplified Schematic Diagram of the ADCMP572 CML Output Stage

Figure 16. Simplified Schematic Diagram of the ADCMP573 RSPECL Output Stage

USING/DISABLING THE LATCH FEATURE

The latch inputs (LE/LE) are active low for latch mode and are internally terminated with 50 Ω resistors to Pin 8. This pin corresponds to and is internally connected to the V_{CCO} supply for the CML-compatible ADCMP572. With the aid of these resistors the ADCMP572 latch function can be disabled by connecting the LE pin to GND with an external pull-down resistor and leaving the LE pin unconnected. To avoid excessive power dissipation, the resistor should be 750 Ω when V \rm_{CCO} = 3.3 V, and 1.2 k Ω when Vcco = 5.2 V. In the PECL-compatible ADCMP573, the V_{TT} pin should be connected externally to the PECL termination supply at V_{CCO} – 2 V. The latch can then be disabled by connecting the LE pin to $V_{\rm CO}$ with an external

500 Ω resistor and leaving the \overline{LE} pin disconnected. In this case, the resistor value does not depend on the V_{CCO} supply voltage.

 V_{CCO} is the signal return for the output stage and V_{CCO} pins should of course be connected to a supply plane for maximum performance.

OPTIMIZING HIGH SPEED PERFORMANCE

As with any high speed comparator, proper design and layout techniques are essential to obtaining the specified performance. Stray capacitance, inductance, inductive power and ground impedances, or other layout issues can severely limit performance and often cause oscillation. Discontinuities along input and output transmission lines can severely limit the specified pulse width dispersion performance.

For applications working in a 50 Ω environment, input and output matching has a significant impact on data dependent (or deterministic) jitter (DJ) and on pulse width dispersion performance. The ADCMP572/ADCMP573 comparators provide internal 50 Ω termination resistors for both the V_P and V_N inputs, and the ADCMP572 provides 50 Ω back terminated outputs. The return side for each input termination is pinned out separately with the V_{TP} and V_{TN} pins, respectively. If a 50 Ω termination is desired at one or both of the V_P/V_N inputs, then the V_{TP} and V_{TN} pins can be connected (or disconnected) to (from) the desired termination potential as required. The termination potential should be carefully bypassed using high quality bypass capacitors as discussed earlier to prevent undesired aberrations on the input signal due to parasitic inductance in the circuit board layout. If a 50 Ω input termination is not desired, either one or both of the V_{TP}/V_{TN} termination pins can be left disconnected. In this case, the pins should be left floating with no external pull-downs or bypassing capacitors.

When leaving an input termination disconnected, the internal resistor acts as a small stub on the input transmission path and can cause problems for very high speed inputs. Reflections should then be expected from the comparator inputs because they no longer provide matched impedance to the input path leading to the device. In this case, it is important to back match the drive source impedance to the input transmission path to minimize multiple reflections. For applications in which the comparator is very close to the driving signal source, the source impedance should be minimized. High source impedance in combination with parasitic input capacitance of the comparator might cause an undesirable degradation in bandwidth at the input, therefore degrading the overall response. Although the ADCMP572/ADCMP573 comparators have been designed to minimize input capacitance, some parasitic capacitance is inevitable. It is therefore recommended that the drive source impedance be no more than 50 Ω for best high speed performance.

COMPARATOR PROPAGATION DELAY DISPERSION

The ADCMP572/ADCMP573 comparators are designed to reduce propagation delay dispersion over a wide input overdrive range of 5 mV to 500 mV. Propagation delay dispersion is variation in the propagation delay that results from a change in the degree of overdrive or slew rate (how far or how fast the input signal exceeds the switching threshold).

Propagation delay dispersion is a specification that becomes important in high speed, time-critical applications such as data communication, automatic test and measurement, instrumentation, and event driven applications such as pulse spectroscopy, nuclear instrumentation, and medical imaging. Dispersion is defined as the variation in propagation delay as the input overdrive conditions vary (Figure 17 and Figure 18). For the ADCMP572/ADCMP573, dispersion is typically <15 ps because the overdrive varies from 10 mV to 500 mV, and the input slew rate varies from 2 V/ns to 10 V/ns. This specification applies for both positive and negative signals since the ADCMP572/ADCMP573 has substantially equal delays for either positive going or negative going inputs.

Figure 18. Propagation Delay—Slew Rate Dispersion

COMPARATOR HYSTERESIS

The addition of hysteresis to a comparator is often desirable in a noisy environment or when the differential input amplitudes are relatively small or slow moving, but excessive hysteresis has a cost in degraded accuracy and slew-induced timing shifts. The transfer function for a comparator with hysteresis is shown in Figure 19. If the input voltage approaches the threshold (0.0 V in this example) from the negative direction, the comparator switches from low to high when the input crosses +VH/2. The new switching threshold becomes −VH/2. The comparator remains in the high state until the threshold $-V_H/2$ is crossed from the positive direction. In this manner, noise centered on 0.0 V input does not cause the comparator to switch states unless it exceeds the region bounded by \pm V_H/2.

Figure 19. Comparator Hysteresis Transfer Function

The customary technique for introducing hysteresis into a comparator uses positive feedback from the output back to the input. A limitation of this approach is that the amount of hysteresis varies with the output logic levels, resulting in hysteresis that can be load dependent and is not symmetrical about the threshold. The external feedback network can also introduce significant parasitics, which reduce high speed performance and can even induce oscillation in some cases.

The ADCMP572/ADCMP573 comparators offer a programmable hysteresis feature that can significantly improve the accuracy and stability of the desired hysteresis. By connecting an external pull-down resistor from the HYS pin to GND, a variable amount of hysteresis can be applied. Leaving the HYS pin disconnected disables the feature, and hysteresis is then less than 1 mV as specified. The maximum hysteresis that can be applied using this method is approximately ±25 mV with the pin grounded. Figure 20 illustrates the amount of hysteresis

applied as a function of external resistor value. The advantages of applying hysteresis in this manner are improved accuracy, stability, and reduced component count. An external bypass capacitor is not recommended on the HYS pin because it would likely degrade the jitter performance of the device. The hysteresis pin could also be driven by a CMOS DAC. It is biased to approximately 250 mV and has an internal series resistance of 600 Ω .

Figure 20. Hysteresis vs. R_{HYS} Control Resistor

MINIMUM INPUT SLEW RATE REQUIREMENTS

As with all high speed comparators, a minimum slew rate requirement must be met to ensure that the device does not oscillate as the input signal crosses the threshold. This oscillation is due in part to the high input bandwidth of the comparator and the feedback parasitics inherent in the package. A minimum slew rate of 50 V/μs should ensure clean output transitions from the ADCMP572/ADCMP573 comparators.

The slew rate may be too slow for other reasons. The extremely high bandwidth of these devices means that broadband noise can be a significant factor when input slew rates are low. There will be at least 120 μv of thermal noise generated over the full comparator bandwidth by two 50 Ω terminations at room temperature. With a slew rate of only 50 V/μs the input will be inside this noise band for over 2 ps, rendering the comparator's jitter performance of 200 fs moot. Raising the slew rate of the input signal and/or reducing the bandwidth over which this resistance is seen at the input can greatly reduce jitter.

TYPICAL APPLICATION CIRCUITS

Figure 21. Zero-Crossing Detector with 3.3 V CML Outputs

Figure 22. LVDS to 50 Ω Back Terminated RSPECL Receiver

Figure 23. Comparator with ±1 V Input Range and 2.5 V or 3.3 V CML Outputs

Figure 24. Comparator with 0 V to 3 V Input Range and 3.3 V or 5.2 V Positive CML Outputs

Figure 25. Interfacing 3.3 V CML to a 50 Ω Ground Terminated Instrument

Figure 26. Disabling the ADCMP572 Latch Feature

Figure 27. Disabling the ADCMP573 Latch Feature

Figure 28. Adding Hysteresis Using the HYS Control Pin

TIMING INFORMATION

Figure 29 illustrates the ADCMP572/ADCMP573 compare and latch timing relationships. Table 4 provides definitions of the terms shown in the figure.

Figure 29. System Timing Diagram

OUTLINE DIMENSIONS

Figure 30. 16-Lead Lead Frame Chip Scale Package [LFCSP_VQ] 3 mm × 3 mm Body, Very Thin Quad (CP-16-2) Dimensions shown in millimeters

ORDERING GUIDE

 $1 Z =$ RoHS Compliant Part.

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